

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
2				*****
3	*			
4	*			Zvector E7 instruction tests for VRR-c encoded:
5	*			
6	*	E7F0	VAVGL	- VECTOR AVERAGE LOGICAL
7	*	E7F2	VAVG	- VECTOR AVERAGE
8	*	E7FC	VMNL	- VECTOR MINIMUM LOGICAL
9	*	E7FD	VMXL	- VECTOR MAXIMUM LOGICAL
10	*	E7FE	VMN	- VECTOR MINIMUM
11	*	E7FF	VMX	- VECTOR MAXIMUM
12	*			
13	*			James Wekel July 2024
14	*			*****
16	*			*****
17	*			
18	*			basic instruction tests
19	*			
20	*			*****
21	*			This program tests proper functioning of the z/arch E7 VRR-c vector
22	*			average, minimum and maximum instructions.
23	*			Exceptions are not tested.
24	*			
25	*			PLEASE NOTE that the tests are very SIMPLE TESTS designed to catch
26	*			obvious coding errors. None of the tests are thorough. They are
27	*			NOT designed to test all aspects of any of the instructions.
28	*			
29	*			*****
30	*			
31	*			*Testcase zvector-e7-01-MinMaxAvg: VECTOR E7 VRR-c instructions
32	*			
33	*			Zvector E7 instruction tests for VRR-c encoded:
34	*			
35	*	*	E7F0	VAVGL - VECTOR AVERAGE LOGICAL
36	*	*	E7F2	VAVG - VECTOR AVERAGE
37	*	*	E7FC	VMNL - VECTOR MINIMUM LOGICAL
38	*	*	E7FD	VMXL - VECTOR MAXIMUM LOGICAL
39	*	*	E7FE	VMN - VECTOR MINIMUM
40	*	*	E7FF	VMX - VECTOR MAXIMUM
41	*	*		
42	*	*	# -----	
43	*	*	# This tests only the basic function of the instruction.	
44	*	*	# Exceptions are NOT tested.	
45	*	*	# -----	
46	*	*		
47	*	main	size	2
48	*	numcpu		1
49	*	sysclear		
50	*	archlvl		z/Arch
51	*			
52	*	loadcore		"\$(testpath)/zvector-e7-01-MinMaxAvg.core" 0x0
53	*			
54	*	diag8cmd	enable	# (needed for messages to Hercules console)
55	*	runttest		2
56	*	diag8cmd	disable	# (reset back to default)

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				57 *
				58 * *Done
				59 *
				60 *****

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
62				*****
63	*			FCHECK Macro - Is a Facility Bit set?
64	*			
65	*			If the facility bit is NOT set, an message is issued and
66	*			the test is skipped.
67	*			
68	*			Fcheck uses R0, R1 and R2
69	*			
70	* eg.			FCHECK 134, 'vector-packed-decimal'
71				*****
72				MACRO
73				FCHECK &BITNO, &NOTSETMSG
74	. *			&BITNO : facility bit number to check
75	. *			&NOTSETMSG : 'facility name'
76	LCLA	&FBBYTE		Facility bit in Byte
77	LCLA	&FBBIT		Facility bit within Byte
78				
79	LCLA	&L(8)		
80	&L(1)	SetA	128, 64, 32, 16, 8, 4, 2, 1	bit positions within byte
81				
82	&FBBYTE	SETA	&BITNO/8	
83	&FBBIT	SETA	&L((&BITNO-(&FBBYTE*8))+1)	
84	. *	MNOTE	0, 'checking Bit=&BITNO: FBBYTE=&FBBYTE, FBBIT=&FBBIT'	
85				
86	B	X&SYSNDX		
87	*			
88	*			Fcheck data area skip message
89	SKT&SYSNDX DC	C'	Skipping tests:	'
90	DC	C&NOTSETMSG		
91	DC	C'	(bit &BITNO) is not installed.	'
92	SKL&SYSNDX EQU	*- SKT&SYSNDX		
93	*			facility bits
94	DS	FD		gap
95	FB&SYSNDX DS	4FD		
96	DS	FD		gap
97	*			
98	X&SYSNDX EQU	*		
99	LA	R0, ((X&SYSNDX- FB&SYSNDX)/8)-1		
100	STFLE	FB&SYSNDX		get facility bits
101				
102	XGR	R0, R0		
103	IC	R0, FB&SYSNDX+&FBBYTE		get fbit byte
104	N	R0, =F' &FBBIT'		is bit set?
105	BNZ	XC&SYSNDX		
106	*			
107	*			facility bit not set, issue message and exit
108	*			
109	LA	R0, SKL&SYSNDX		message length
110	LA	R1, SKT&SYSNDX		message address
111	BAL	R2, MSG		
112				
113	B	EOJ		
114	XC&SYSNDX EQU	*		
115		MEND		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				117 **** 118 * Low core PSWs 119 ****	*****
00000000		00000000 00000000	0000244F	120 ZVE7TST START 0 121 USING ZVE7TST, R0	Low core addressability
		00000140	00000000	122 123 SVOLDPSW EQU ZVE7TST+X'140'	z/Arch Supervisor call old PSW
00000000		00000000 000001A0	125	ORG	ZVE7TST+X'1A0'
000001A0	00000001 80000000	00000000 000001A0	126	DC	X'0000000180000000'
000001A8	00000000 00000200		127	DC	AD(BEGIN)
000001B0		000001B0 000001D0	129	ORG	ZVE7TST+X'1D0'
000001D0	00020001 80000000	00000000 00000200	130	DC	X'0002000180000000'
000001D8	00000000 0000DEAD		131	DC	AD(X' DEAD')
000001E0		000001E0 00000200	133	ORG	ZVE7TST+X'200'
					Start of actual test program..
				135 **** 136 * The actual "ZVE7TST" program itself... 137 ****	*****
				138 * 139 * Architecture Mode: z/Arch 140 * Register Usage:	
				141 * 142 * R0 (work) 143 * R1-4 (work)	
				144 * R5 Testing control table - current test base 145 * R6-R7 (work)	
				146 * R8 First base register 147 * R9 Second base register 148 * R10 Third base register 149 * R11 E7TEST call return	
				150 * R12 E7TESTS register 151 * R13 (work) 152 * R14 Subroutine call 153 * R15 Secondary Subroutine call or work 154 * 155 ****	
00000200		00000200	157	USING BEGIN, R8	FIRST Base Register
00000200		00001200	158	USING BEGIN+4096, R9	SECOND Base Register
00000200		00002200	159	USING BEGIN+8192, R10	THIRD Base Register
00000200	0580		161 BEGIN	BALR R8, 0	Initialize FIRST base register
00000202	0680		162	BCTR R8, 0	Initialize FIRST base register
00000204	0680		163	BCTR R8, 0	Initialize FIRST base register
00000206	4190 8800	00000800	165	LA R9, 2048(, R8)	Initialize SECOND base register
0000020A	4190 9800	00000800	166	LA R9, 2048(, R9)	Initialize SECOND base register
			167		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
0000020E	41A0 9800		00000800	168 LA R10, 2048(, R9)	Initialize THIRD base register	
00000212	41A0 A800		00000800	169 LA R10, 2048(, R10)	Initialize THIRD base register	
				170		
00000216	B600 828C		0000048C	171 STCTL R0, R0, CTLR0	Store CRO to enable AFP	
0000021A	9604 828D		0000048D	172 OI CTLR0+1, X'04'	Turn on AFP bit	
0000021E	9602 828D		0000048D	173 OI CTLR0+1, X'02'	Turn on Vector bit	
00000222	B700 828C		0000048C	174 LCTL R0, R0, CTLR0	Reload updated CRO	
				175		
				176 *****	*****	
				177 * Is Vector packed-decimal facility installed (bit 134)	*****	
				178 *****	*****	
				179		
00000226	47F0 80A8		000002A8	180 FCHECK 129, 'z/Architecture vector facility'		
				181+ B X0001		
				182+*	Fcheck data area	
				183+*	skip message	
0000022A	40404040 E2928997			184+SKT0001 DC C' Skipping tests: '		
0000023E	A961C199 838889A3			185+ DC C' z/Architecture vector facility'		
0000025C	404D8289 A340F1F2			186+ DC C' (bit 129) is not installed.'		
		0000004E	00000001	187+SKL0001 EQU *- SKT0001		
				188+*	facility bits	
00000278	00000000 00000000			189+ DS FD	gap	
00000280	00000000 00000000			190+FB0001 DS 4FD		
000002A0	00000000 00000000			191+ DS FD	gap	
				192+*		
		000002A8	00000001	193+X0001 EQU *		
000002A8	4100 0004		00000004	194+ LA R0, ((X0001-FB0001)/8)-1		
000002AC	B2B0 8080		00000280	195+ STFLE FB0001	get facility bits	
000002B0	B982 0000			196+ XGR R0, R0		
000002B4	4300 8090		00000290	197+ IC R0, FB0001+16	get fbit byte	
000002B8	5400 8294		00000494	198+ N R0, =F'64'	is bit set?	
000002BC	4770 80D0		000002D0	199+ BNZ XC0001		
				200+*		
				201+* facility bit not set, issue message and exit		
				202+*		
000002C0	4100 004E		0000004E	203+ LA R0, SKL0001	message length	
000002C4	4110 802A		0000022A	204+ LA R1, SKT0001	message address	
000002C8	4520 81A8		000003A8	205+ BAL R2, MSG		
000002CC	47F0 8270		00000470	206+ B EOJ		
		000002D0	00000001	207+XC0001 EQU *		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				209 **** 210 *	Do tests in the E7TESTS table		
				211 **** 212			
000002D0	58C0 8298		00000498	213 L R12, =A(E7TESTS)	get table of test addresses		
				214			
000002D4	5850 C000	000002D4	00000001 00000000	215 NEXTE6 EQU * 216 L R5, 0(0, R12)	get test address		
000002D8	1255			217 LTR R5, R5	have a test?		
000002DA	4780 811E		0000031E	218 BZ ENDTEST 219	done?		
000002DE		00000000		220 USING E7TEST, R5 221			
000002DE	4800 5004		00000004	222 LH R0, TNUM	save current test number		
000002E2	5000 8E04		00001004	223 ST R0, TESTING	for easy reference		
000002E6	E710 8E94 0006		00001094	225 VL V1, V1FUDGE			
000002EC	58B0 5000		00000000	226 L R11, TSUB	get address of test routine		
000002F0	05BB			227 BALR R11, R11 228	do test		
000002F2	E310 501C 0014		0000001C	229 LGF R1, READDR	get address of expected result		
000002F8	D50F 5028 1000	00000028	00000000	230 CLC V10OUTPUT, 0(R1)	valid?		
000002FE	4770 810A		0000030A	231 BNE FAILMSG	no, issue failed message		
00000302	41C0 C004		00000004	232 LA R12, 4(0, R12)	next test address		
00000306	47F0 80D4		000002D4	233 B NEXTE6			

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				236 **** 237 * result not as expected: 238 * issue message with test number, instruction under test 239 * and instruction m4 240 ****
0000030A	45F0 812C	0000030A	00000001 0000032C	241 FAILMSG EQU * 242 BAL R15, RPERROR
				244 **** 245 * continue after a failed test 246 ****
0000030E	5800 829C	0000030E	00000001 0000049C	247 FAILCONT EQU * 248 L R0, =F'1' set failed test indicator 249 ST R0, FAILED
00000312	5000 8E00		00001000	250
00000316	41C0 C004		00000004	251 LA R12, 4(0, R12) next test address 0000031A 47F0 80D4 000002D4 252 B NEXTE6
				254 **** 255 * end of testing; set ending psw 256 ****
0000031E	5810 8E00	0000031E	00000001 00001000	257 ENDTEST EQU * 258 L R1, FAILED did a test fail? 259 LTR R1, R1
00000322	1211			260 BZ EOJ No, exit 00000324 4780 8270 00000470 261 B FAILTEST Yes, exit with BAD PSW 00000328 47F0 8288 00000488

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				263 ****	*****	*****
				264 * RPTERROR		Report instruction test in error
				265 ****	*****	*****
0000032C	50F0 8190		00000390	267 RPTERROR ST	R15, RPTSAVE	Save return address
00000330	5050 8194		00000394	268 ST	R5, RPTSVR5	Save R5
00000334	4820 5004		00000004	269 * 270 LH	R2, TNUM	get test number and convert
00000338	4E20 8E73		00001073	271 CVD	R2, DECNUM	
0000033C	D211 8E5D 8E47	0000105D	00001047	272 MVC	PRT3, EDIT	
00000342	DE11 8E5D 8E73	0000105D	00001073	273 ED	PRT3, DECNUM	
00000348	D202 8E18 8E6A	00001018	0000106A	274 275 MVC	PRTNUM(3), PRT3+13	fill in message with test #
0000034E	D207 8E33 5008	00001033	00000008	276 277 *	PRTNAME, OPNAME	fill in message with instruction
00000354	E320 5007 0076		00000007	278 LB	R2, m4	get m4 and convert
0000035A	4E20 8E73		00001073	279 CVD	R2, DECNUM	
0000035E	D211 8E5D 8E47	0000105D	00001047	280 MVC	PRT3, EDIT	
00000364	DE11 8E5D 8E73	0000105D	00001073	281 ED	PRT3, DECNUM	
0000036A	D201 8E44 8E6B	00001044	0000106B	282 MVC	PRTM4(2), PRT3+14	fill in message with m4 field
				284 *		
				285 *	Use Hercules Diagnose for Message to console	
				286 *		
00000370	9002 8198		00000398	287 STM	R0, R2, RPTDWSAV	save regs used by MSG
00000374	4100 003F		0000003F	288 LA	R0, PRTLNG	message length
00000378	4110 8E08		00001008	289 LA	R1, PRTLINE	message address
0000037C	4520 81A8		000003A8	290 BAL	R2, MSG	call Hercules console MSG display
00000380	9802 8198		00000398	291 LM	R0, R2, RPTDWSAV	restore regs
00000384	5850 8194		00000394	293 L	R5, RPTSVR5	Restore R5
00000388	58F0 8190		00000390	294 L	R15, RPTSAVE	Restore return address
0000038C	07FF			295 BR	R15	Return to caller
00000390	00000000			297 RPTSAVE DC	F' 0'	R15 save area
00000394	00000000			298 RPTSVR5 DC	F' 0'	R5 save area
00000398	00000000 00000000			300 RPTDWSAV DC	2D' 0'	R0-R2 save area for MSG call

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				302 **** 303 * Issue HERCULES MESSAGE pointed to by R1, length in R0 304 * R2 = return address 305 ****		
000003A8	4900 82A0		000004A0	307 MSG CH R0, =H' 0' 308 BNHR R2		Do we even HAVE a message? No, ignore
000003AC	07D2					
000003AE	9002 81E4		000003E4	310 STM R0, R2, MSGSAVE		Save registers
000003B2	4900 82A2		000004A2	312 CH R0, =AL2(L' MSGMSG)		Message length within limits?
000003B6	47D0 81BE		000003BE	313 BNH MSGOK		Yes, continue
000003BA	4100 005F		0000005F	314 LA R0, L' MSGMSG		No, set to maximum
000003BE	1820			316 MSGOK LR R2, R0		Copy length to work register
000003C0	0620			317 BCTR R2, 0		Minus-1 for execute
000003C2	4420 81F0		000003F0	318 EX R2, MSGMVC		Copy message to O/P buffer
000003C6	4120 200A		0000000A	320 LA R2, 1+L' MSGCMD(, R2)		Calculate true command length
000003CA	4110 81F6		000003F6	321 LA R1, MSGCMD		Point to true command
000003CE	83120008			323 DC X' 83', X' 12', X' 0008'		Issue Hercules Diagnose X' 008'
000003D2	4780 81DE		000003DE	324 BZ MSGRET		Return if successful
000003D6	1222			325		
000003D8	4780 81DE		000003DE	326 LTR R2, R2 327 BZ MSGRET 328		Is Diag8 Ry (R2) 0? an error occurred but continue
000003DC	0000			329 DC H' 0'		CRASH for debugging purposes
000003DE	9802 81E4		000003E4	331 MSGRET LM R0, R2, MSGSAVE		Restore registers
000003E2	07F2			332 BR R2		Return to caller
000003E4	00000000 00000000			334 MSGSAVE DC 3F' 0'		Registers save area
000003F0	D200 81FF 1000	000003FF	00000000	335 MSGMVC MVC MSGMSG(0), 0(R1)		Executed instruction
000003F6	D4E2C7D5 D6C8405C			337 MSGCMD DC C' MSGNOH * '		*** HERCULES MESSAGE COMMAND ***
000003FF	40404040 40404040			338 MSGMSG DC CL95' '		The message text to be displayed
000003F7	00000000 00000000			339		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				341 **** 342 * Normal completion or Abnormal termination PSWs 343 ****	*****
00000460	00020001 80000000			345 EOJPSW DC OD' 0' , X' 0002000180000000' , AD(0)	
00000470	B2B2 8260	00000460	347 EOJ LPSWE EOJPSW		Normal completion
00000478	00020001 80000000			349 FAILPSW DC OD' 0' , X' 0002000180000000' , AD(X' BAD')	
00000488	B2B2 8278	00000478	351 FAILTEST LPSWE FAILPSW		Abnormal termination
				353 **** 354 * Working Storage 355 ****	*****
0000048C	00000000		357 CTLR0 DS F		CR0
00000490	00000000		358 DS F		
00000494			360 LTORG ,		Literals pool
00000494	00000040		361 =F' 64'		
00000498	000023C0		362 =A(E7TESTS)		
0000049C	00000001		363 =F' 1'		
000004A0	0000		364 =H' 0'		
000004A2	005F		365 =AL2(L' MSGMSG)		
			366		
			367 *	some constants	
			368		
		00000400 00000001	369 K EQU 1024		One KB
		00001000 00000001	370 PAGE EQU (4*K)		Size of one page
		00010000 00000001	371 K64 EQU (64*K)		64 KB
		00100000 00000001	372 MB EQU (K*K)		1 MB
			373		
		AABBCCDD 00000001	374 REG2PATT EQU X' AABBCCDD'		Polluted Register pattern
		000000DD 00000001	375 REG2LOW EQU X' DD'		(last byte above)

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				377 *=====
				378 *
				379 * NOTE: start data on an address that is easy to display
				380 * within Hercules
				381 *
				382 *=====
				383
000004A4		000004A4	00001000	384 ORG ZVE7TST+X'1000'
00001000	00000000			385 FAILED DC F'0'
00001004	00000000			386 TESTING DC F'0'
				some test failed? current test number
				388 *
				389 * failed message and associated editting
				390 *
00001008	40404040 40404040			391 PRTLINE DC C' Test # '
00001018	A7A7A7			392 PRTNUM DC C' xxx'
0000101B	40868189 93858440			393 DC c' failed for instruction '
00001033	A7A7A7A7 A7A7A7A7			394 PRTNAME DC CL8'xxxxxxxx'
0000103B	40A689A3 884094F4			395 DC C' with m4='
00001044	A7A7			396 PRTm4 DC C' xx'
00001046	4B	0000003F	00000001	397 DC C' .'
				398 PRTLNG EQU *-PRTLINE

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				418 **** 419 * E7TEST DSECT 420 ****
00000000	00000000			422 E7TEST DSECT ,
00000004	0000			423 TSUB DC A(0)
00000006	00			424 TNUM DC H'00'
00000007	00			425 DC X'00'
				426 M4 DC HL1'00'
				427
00000008	40404040 40404040			428 OPNAME DC CL8' '
00000010	00000000			429 V2ADDR DC A(0)
00000014	00000000			430 V3ADDR DC A(0)
00000018	00000000			431 RELEN DC A(0)
0000001C	00000000			432 READDR DC A(0)
00000020	00000000 00000000			433 DS FD
00000028	00000000 00000000			434 V1OUTPUT DS XL16
00000038	00000000 00000000			435 DS FD
				436
				437 * test routine will be here (from VRR-c macro)
				438 *
				439 * followed by
				440 * EXPECTED RESULT
000010B4	00000000 0000244F			442 ZVE7TST CSECT ,
				443 DS OF
				445 ****
				446 * Macros to help build test tables
				447 ****
				449 *
				450 * macro to generate individual test
				451 *
				452 MACRO
				453 VRR_C &INST, &M4
				454 . * &INST - VRR-c instruction under test
				455 . * &m4 - m3 field
				456
				457 GBLA &TNUM
				458 &TNUM SETA &TNUM+1
				459
				460 DS OFD
				461 USING *, R5
				462 base for test data and test routine
				463 T&TNUM DC A(X&TNUM)
				464 DC H'&TNUM
				465 DC X'00'
				466 DC HL1'&M4'
				467 DC CL8'&INST'
				468 DC A(RE&TNUM+16)
				address of test routine test number
				m4
				instruction name
				address of v2 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
469		DC	A(RE&TNUM+32)		address of v3 source
470		DC	A(16)		result length
471	REA&TNUM	DC	A(RE&TNUM)		result address
472		DS	FD		gap
473	V10&TNUM	DS	XL16		V1 output
474		DS	FD		gap
475	.	*			
476	*				
477	X&TNUM	DS	OF		
478		LGF	R1, V2ADDR		load v2 source
479		VL	v22, 0(R1)		use v22 to test decoder
480					
481		LGF	R1, V3ADDR		load v3 source
482		VL	v23, 0(R1)		use v23 to test decoder
483					
484		&INST	V22, V22, V23, &M4		test instruction (dest is a source)
485		VST	V22, V10&TNUM		save v1 output
486					
487		BR	R11		return
488					
489	RE&TNUM	DC	OF		xl16 expected result
490					
491		DROP	R5		
492		MEND			
493	*				
494	*				
495	*	macro	to generate table of pointers to individual tests		
496	*				
497			MACRO		
498			PTTABLE		
499			GBLA &TNUM		
500			LCLA &CUR		
501	&CUR		SETA 1		
502	.	*			
503	TTABLE	DS	OF		
504	. LOOP	ANOP			
505	.	*			
506		DC	A(T&CUR)		TEST &CUR
507	.	*			
508	&CUR	SETA	&CUR+1		
509		AIF	(&CUR LE &TNUM). LOOP		
510	*				
511		DC	A(0)		END OF TABLE
512		DC	A(0)		
513	.	*			
514		MEND			
515					

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				517 **** 518 * E6 VRR-c tests 519 **** 520 PRINT DATA 521	*****
				522 * E7F0 VAVGL - VECTOR AVERAGE LOGICAL 523 * E7F2 VAVG - VECTOR AVERAGE 524 * E7FC VMNL - VECTOR MINIMUM LOGICAL 525 * E7FD VMKL - VECTOR MAXIMUM LOGICAL 526 * E7FE VMN - VECTOR MINIMUM 527 * E7FF VMX - VECTOR MAXIMUM 528	*****
				529 * VRR-c instruction, m4 530 * followed by 531 * 16 byte expected result (V1) 532 * 16 byte V2 source 533 * 16 byte V3 source 534 * -	*****
				535 * VMX - VECTOR MAXIMUM 536 * -	*****
				537 * Byte	*****
000010B8				538 VRR_C VMX, 0 539+ DS OFD	base for test data and test routine
000010B8	000010F8	000010B8		540+ USING *, R5 541+T1 DC A(X1)	address of test routine
000010BC	0001			542+ DC H' 1'	test number
000010BE	00			543+ DC X' 00'	m4
000010BF	00			544+ DC HL1' 0'	instruction name
000010C0	E5D4E740 40404040			545+ DC CL8' VMX'	address of v2 source
000010C8	00001130			546+ DC A(RE1+16)	address of v3 source
000010CC	00001140			547+ DC A(RE1+32)	result length
000010D0	00000010			548+ DC A(16)	result address
000010D4	00001120			549+REA1 DC A(RE1)	gap
000010D8	00000000 00000000			550+ DS FD	V1 output
000010E0	00000000 00000000			551+V101 DS XL16	
000010E8	00000000 00000000			552+ DS FD	gap
000010F0	00000000 00000000			553+*	
000010F8				554+X1 DS OF	load v2 source
000010F8	E310 5010 0014		00000010	555+ LGF R1, V2ADDR	use v22 to test decoder
000010FE	E761 0000 0806		00000000	556+ VL v22, 0(R1)	load v3 source
00001104	E310 5014 0014		00000014	557+ LGF R1, V3ADDR	use v23 to test decoder
0000110A	E771 0000 0806		00000000	558+ VL v23, 0(R1)	test instruction (dest is a source)
00001110	E766 7000 0EFF			559+ VMX V22, V22, V23, 0	
00001116	E760 5028 080E		000010E0	560+ VST V22, V101	save v1 output
0000111C	07FB			561+ BR R11	return
00001120				562+REA1 DC OF	xl16 expected result
00001120	02030405 09010181			563+ DROP R5	
00001128	070FFFFE 00000020			564 DC XL16' 0203040509010181070FFFFE00000020'	expected result
00001130	01020304 09800181			565 DC XL16' 0102030409800181070FFF0000001F'	v2
00001138	070FFFFD 0000001F			566 DC XL16' 020304050001FF80010AFEFE00000020'	v3
00001140	02030405 0001FF80			567	
00001148	010AFEEF 00000020			568 * Halfword	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001150				569 570+ DS	VRR_C VMX, 1 OFD	
00001150		00001150		571+ USING *, R5		base for test data and test routine
00001150	00001190			572+T2 DC	A(X2)	address of test routine
00001154	0002			573+ DC	H' 2'	test number
00001156	00			574+ DC	X' 00'	
00001157	01			575+ DC	HL1' 1'	m4
00001158	E5D4E740 40404040			576+ DC	CL8' VMX'	instruction name
00001160	000011C8			577+ DC	A(RE2+16)	address of v2 source
00001164	000011D8			578+ DC	A(RE2+32)	address of v3 source
00001168	00000010			579+ DC	A(16)	result length
0000116C	000011B8			580+REA2 DC	A(RE2)	result address
00001170	00000000 00000000			581+ DS	FD	gap
00001178	00000000 00000000			582+V102 DS	XL16	V1 output
00001180	00000000 00000000			583+ DS	FD	gap
00001188	00000000 00000000			584+*		
00001190				585+X2 DS	OF	
00001190	E310 5010 0014	00000010		586+ LGF	R1, V2ADDR	load v2 source
00001196	E761 0000 0806	00000000		587+ VL	v22, 0(R1)	use v22 to test decoder
0000119C	E310 5014 0014	00000014		588+ LGF	R1, V3ADDR	load v3 source
000011A2	E771 0000 0806	00000000		589+ VL	v23, 0(R1)	use v23 to test decoder
000011A8	E766 7000 1EFF			590+ VMX	V22, V22, V23, 1	test instruction (dest is a source)
000011AE	E760 5028 080E	00001178		591+ VST	V22, V102	save v1 output
000011B4	07FB			592+ BR	R11	return
000011B8				593+RE2 DC	OF	xl16 expected result
000011B8				594+ DROP	R5	
000011B8	00020001 FFFE0001			595 DC	XL16' 00020001FFFE00017FFF800112340020'	expected result
000011C0	7FFF8001 12340020			596 DC	XL16' 0001FFFFFD80007FFF80000123001F'	v2
000011C8	0001FFFF FFFD8000			597 DC	XL16' 00020001FFFE000100AA800112340020'	v3
000011D0	7FFF8000 0123001F			598		
000011D8	00020001 FFFE0001			599 * Word		
000011E0	00AA8001 12340020			600 VRR_C VMX, 2		
000011E8				601+ DS	OFD	
000011E8		000011E8		602+ USING *, R5		base for test data and test routine
000011E8	00001228			603+T3 DC	A(X3)	address of test routine
000011EC	0003			604+ DC	H' 3'	test number
000011EE	00			605+ DC	X' 00'	
000011EF	02			606+ DC	HL1' 2'	m4
000011F0	E5D4E740 40404040			607+ DC	CL8' VMX'	instruction name
000011F8	00001260			608+ DC	A(RE3+16)	address of v2 source
000011FC	00001270			609+ DC	A(RE3+32)	address of v3 source
00001200	00000010			610+ DC	A(16)	result length
00001204	00001250			611+REA3 DC	A(RE3)	result address
00001208	00000000 00000000			612+ DS	FD	gap
00001210	00000000 00000000			613+V103 DS	XL16	V1 output
00001218	00000000 00000000			614+ DS	FD	gap
00001220	00000000 00000000			615+*		
00001228				616+X3 DS	OF	
00001228	E310 5010 0014	00000010		617+ LGF	R1, V2ADDR	load v2 source
0000122E	E761 0000 0806	00000000		618+ VL	v22, 0(R1)	use v22 to test decoder
00001234	E310 5014 0014	00000014		619+ LGF	R1, V3ADDR	load v3 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
0000123A	E771 0000 0806		00000000	620+ VL v23, 0(R1)		
00001240	E766 7000 2EFF			621+ VMX V22, V22, V23, 2	use v23 to test decoder	
00001246	E760 9010 080E		00001210	622+ VST V22, V103	test instruction (dest is a source)	
0000124C	07FB			623+ BR R11	save v1 output	
00001250				624+RE3 DC OF	return	
00001250				625+ DROP R5	xl16 expected result	
00001250	FFFFFFF 7FFFFFF			626 DC XL16' FFFFFFF7FFFFFF1234567800000020'	expected result	
00001258	12345678 00000020			627 DC XL16' FFFFFFF7FFFFFF012345670000001F'	v2	
00001260	FFFFFFF 7FFFFFF			628 DC XL16' FFFFFFFE0000000A1234567800000020'	v3	
00001268	01234567 0000001F					
00001270	FFFFFFF 0000000A					
00001278	12345678 00000020					
				629		
				630 * Doubl eword		
00001280				631 VRR_C VMX, 3		
00001280		00001280		632+ DS OFD		
00001280	000012C0			633+ USING *, R5	base for test data and test routine	
00001284	0004			634+T4 DC A(X4)	address of test routine	
00001286	00			635+ DC H' 4'	test number	
00001287	03			636+ DC X' 00'		
00001288	E5D4E740 40404040			637+ DC HL1' 3'	m4	
00001290	000012F8			638+ DC CL8' VMX'	instruction name	
00001294	00001308			639+ DC A(RE4+16)	address of v2 source	
00001298	00000010			640+ DC A(RE4+32)	address of v3 source	
0000129C	000012E8			641+ DC A(16)	result length	
000012A0	00000000 00000000			642+REA4 DC A(RE4)	result address	
000012A8	00000000 00000000			643+ DS FD	gap	
000012B0	00000000 00000000			644+V104 DS XL16	V1 output	
000012B8	00000000 00000000			645+ DS FD	gap	
				646+*		
000012C0				647+X4 DS OF		
000012C0	E310 5010 0014		00000010	648+ LGF R1, V2ADDR	load v2 source	
000012C6	E761 0000 0806		00000000	649+ VL v22, 0(R1)	use v22 to test decoder	
000012CC	E310 5014 0014		00000014	650+ LGF R1, V3ADDR	load v3 source	
000012D2	E771 0000 0806		00000000	651+ VL v23, 0(R1)	use v23 to test decoder	
000012D8	E766 7000 3EFF			652+ VMX V22, V22, V23, 3	test instruction (dest is a source)	
000012DE	E760 5028 080E		000012A8	653+ VST V22, V104	save v1 output	
000012E4	07FB			654+ BR R11	return	
000012E8				655+RE4 DC OF	xl16 expected result	
000012E8				656+ DROP R5		
000012E8	FFFFFFF FFFFFFF			657 DC XL16' FFFFFFFFFFFFFF0000000000000020'	expected result	
000012F0	00000000 00000020			658 DC XL16' FFFFFFFFFFFFFF000000000000001F'	v2	
000012F8	FFFFFFF FFFFFFF			659 DC XL16' FFFFFFFFFFFFFD0000000000000020'	v3	
00001300	00000000 0000001F					
00001308	FFFFFFF FFFFFFFD					
00001310	00000000 00000020					
				660		
				661 *		
				662 * VMXL - VECTOR MAXIMUM LOGICAL		
				663 *		
				664 * Byte		
00001318				665 VRR_C VMXL, 0		
00001318		00001318		666+ DS OFD		
00001318	00001358			667+ USING *, R5	base for test data and test routine	
				668+T5 DC A(X5)	address of test routine	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
0000131C	0005			669+ DC H' 5'	test number	
0000131E	00			670+ DC X' 00'		
0000131F	00			671+ DC HL1' 0'	m4	
00001320	E5D4E7D3 40404040			672+ DC CL8' VMKL'	instruction name	
00001328	00001390			673+ DC A(REQ+16)	address of v2 source	
0000132C	000013A0			674+ DC A(REQ+32)	address of v3 source	
00001330	00000010			675+ DC A(16)	result length	
00001334	00001380			676+RE5 DC A(REQ)	result address	
00001338	00000000 00000000			677+ DS FD	gap	
00001340	00000000 00000000			678+V105 DS XL16	V1 output	
00001348	00000000 00000000					
00001350	00000000 00000000			679+ DS FD	gap	
				680+*		
				681+X5 DS OF		
00001358	E310 5010 0014		00000010	682+ LGF R1, V2ADDR	load v2 source	
0000135E	E761 0000 0806		00000000	683+ VL v22, 0(R1)	use v22 to test decoder	
00001364	E310 5014 0014		00000014	684+ LGF R1, V3ADDR	load v3 source	
0000136A	E771 0000 0806		00000000	685+ VL v23, 0(R1)	use v23 to test decoder	
00001370	E766 7000 0EFD		00000000	686+ VMKL V22, V22, V23, 0	test instruction (dest is a source)	
00001376	E760 5028 080E		00001340	687+ VST V22, V105	save v1 output	
0000137C	07FB			688+ BR R11	return	
00001380				689+RE5 DC OF	XL16 expected result	
00001380				690+ DROP R5		
00001380	02030405 0980FF81			691 DC XL16' 020304050980FF81070FFFFE00000020'	expected result	
00001388	070FFFFE 00000020					
00001390	01020304 09800181			692 DC XL16' 0102030409800181070FFFFD0000001F'	v2	
00001398	070FFFFD 0000001F					
000013A0	02030405 0001FF80			693 DC XL16' 020304050001FF80010AFEFE00000020'	v3	
000013A8	010AFEEF 00000020					
				694		
				695 * Halfword		
				696 VRR_C VMKL, 1		
000013B0				697+ DS OFD		
000013B0		000013B0		698+ USING *, R5	base for test data and test routine	
000013B0	000013F0			699+T6 DC A(X6)	address of test routine	
000013B4	0006			700+ DC H' 6'	test number	
000013B6	00			701+ DC X' 00'		
000013B7	01			702+ DC HL1' 1'	m4	
000013B8	E5D4E7D3 40404040			703+ DC CL8' VMKL'	instruction name	
000013C0	00001428			704+ DC A(REQ+16)	address of v2 source	
000013C4	00001438			705+ DC A(REQ+32)	address of v3 source	
000013C8	00000010			706+ DC A(16)	result length	
000013CC	00001418			707+RE6 DC A(REQ)	result address	
000013D0	00000000 00000000			708+ DS FD	gap	
000013D8	00000000 00000000			709+V106 DS XL16	V1 output	
000013E0	00000000 00000000					
000013E8	00000000 00000000			710+ DS FD	gap	
				711+*		
				712+X6 DS OF		
000013F0	E310 5010 0014		00000010	713+ LGF R1, V2ADDR	load v2 source	
000013F6	E761 0000 0806		00000000	714+ VL v22, 0(R1)	use v22 to test decoder	
000013FC	E310 5014 0014		00000014	715+ LGF R1, V3ADDR	load v3 source	
00001402	E771 0000 0806		00000000	716+ VL v23, 0(R1)	use v23 to test decoder	
00001408	E766 7000 1EFD		00000000	717+ VMKL V22, V22, V23, 1	test instruction (dest is a source)	
0000140E	E760 5028 080E		000013D8	718+ VST V22, V106	save v1 output	
00001414	07FB			719+ BR R11	return	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001418				720+RE6	DC	OF	xl16 expected result
00001418				721+	DROP	R5	
00001418	0002FFFF FFFE8000			722	DC	XL16' 0002FFFFFFE80007FFF800112340020'	expected result
00001420	7FFF8001 12340020			723	DC	XL16' 0001FFFFFFD80007FFF80000123001F'	v2
00001428	0001FFFF FFD8000			724	DC	XL16' 00020001FFFE000100AA800112340020'	v3
00001430	7FFF8000 0123001F			725			
00001438	00020001 FFFE0001			726 * Word			
00001440	00AA8001 12340020			727	VRR_C	VMXL, 2	
00001448				728+	DS	OFD	
00001448		00001448		729+	USING	*, R5	base for test data and test routine
00001448	00001488			730+T7	DC	A(X7)	address of test routine
0000144C	0007			731+	DC	H' 7'	test number
0000144E	00			732+	DC	X' 00'	
0000144F	02			733+	DC	HL1' 2'	m4
00001450	E5D4E7D3 40404040			734+	DC	CL8' VMXL'	instruction name
00001458	000014C0			735+	DC	A(RE7+16)	address of v2 source
0000145C	000014D0			736+	DC	A(RE7+32)	address of v3 source
00001460	00000010			737+	DC	A(16)	result length
00001464	000014B0			738+REA7	DC	A(RE7)	result address
00001468	00000000 00000000			739+	DS	FD	gap
00001470	00000000 00000000			740+V107	DS	XL16	V1 output
00001478	00000000 00000000			741+	DS	FD	gap
00001480	00000000 00000000			742+*			
00001488				743+X7	DS	OF	
00001488	E310 5010 0014	00000010		744+	LGF	R1, V2ADDR	load v2 source
0000148E	E761 0000 0806	00000000		745+	VL	v22, 0(R1)	use v22 to test decoder
00001494	E310 5014 0014	00000014		746+	LGF	R1, V3ADDR	load v3 source
0000149A	E771 0000 0806	00000000		747+	VL	v23, 0(R1)	use v23 to test decoder
000014A0	E766 7000 2EFD			748+	VMXL	V22, V22, V23, 2	test instruction (dest is a source)
000014A6	E760 5028 080E	00001470		749+	VST	V22, V107	save v1 output
000014AC	07FB			750+	BR	R11	return
000014B0				751+RE7	DC	OF	xl16 expected result
000014B0				752+	DROP	R5	
000014B0	FFFFFFF7FFFFFFF			753	DC	XL16' FFFFFFFF7FFFFFFF1234567800000020'	expected result
000014B8	12345678 00000020			754	DC	XL16' FFFFFFFF7FFFFFFF012345670000001F'	v2
000014C0	FFFFFFF7FFFFFFF			755	DC	XL16' FFFFFFFE0000000A1234567800000020'	v3
000014C8	01234567 0000001F			756			
000014D0	FFFFFFFE 0000000A			757 * Doubleword			
000014D8	12345678 00000020			758	VRR_C	VMXL, 3	
000014E0				759+	DS	OFD	
000014E0		000014E0		760+	USING	*, R5	base for test data and test routine
000014E0	00001520			761+T8	DC	A(X8)	address of test routine
000014E4	0008			762+	DC	H' 8'	test number
000014E6	00			763+	DC	X' 00'	
000014E7	03			764+	DC	HL1' 3'	m4
000014E8	E5D4E7D3 40404040			765+	DC	CL8' VMXL'	instruction name
000014F0	00001558			766+	DC	A(RE8+16)	address of v2 source
000014F4	00001568			767+	DC	A(RE8+32)	address of v3 source
000014F8	00000010			768+	DC	A(16)	result length

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000014FC	00001548			769+REA8	DC	A(REQ)
00001500	00000000 00000000			770+	DS	FD
00001508	00000000 00000000			771+V108	DS	XL16
00001510	00000000 00000000			772+	DS	FD
00001518	00000000 00000000			773+*		gap
00001520				774+X8	DS	OF
00001520	E310 5010 0014	00000010		775+	LGF	R1, V2ADDR
00001526	E761 0000 0806	00000000		776+	VL	v22, 0(R1)
0000152C	E310 5014 0014	00000014		777+	LGF	R1, V3ADDR
00001532	E771 0000 0806	00000000		778+	VL	v23, 0(R1)
00001538	E766 7000 3EFD			779+	VMXL	V22, V22, V23, 3
0000153E	E760 5028 080E	00001508		780+	VST	V22, V108
00001544	07FB			781+	BR	R11
00001548				782+RE8	DC	OF
00001548				783+	DROP	R5
00001548	FFFFFF FFFFFFFF			784	DC	XL16' FFFFFFFFFFFFFF0000000000000020'
00001550	00000000 00000020			785	DC	XL16' FFFFFFFFFFFFFF000000000000001F'
00001558	FFFFFF FFFFFFFF					v2
00001560	00000000 0000001F			786	DC	XL16' FFFFFFFFFFFFFD0000000000000020'
00001568	FFFFFF FFFFFFFD					v3
00001570	00000000 00000020			787		
				788 *-		
				789 * VMN - VECTOR MINIMUM		
				790 *-		
				791 * Byte		
00001578		00001578		792 VRR_C VMN, 0		
00001578	000015B8	00001578		793+ DS OFD		
00001578	0009			794+ USING *, R5		base for test data and test routine
0000157C	0009			795+T9 DC A(X9)		address of test routine
0000157E	00			796+ DC H' 9'		test number
0000157F	00			797+ DC X' 00'		
00001580	E5D4D540 40404040			798+ DC HL1' 0'		m4
00001588	000015F0			799+ DC CL8' VMN'		instruction name
0000158C	00001600			800+ DC A(REQ+16)		address of v2 source
00001590	00000010			801+ DC A(REQ+32)		address of v3 source
00001594	000015E0			802+ DC A(16)		result length
00001598	00000000 00000000			803+REA9 DC A(REQ)		result address
000015A0	00000000 00000000			804+ DS FD		gap
000015A8	00000000 00000000			805+V109 DS XL16		V1 output
000015B0	00000000 00000000			806+ DS FD		gap
				807+*		
000015B8				808+X9 DS OF		
000015B8	E310 5010 0014	00000010		809+ LGF R1, V2ADDR		load v2 source
000015BE	E761 0000 0806	00000000		810+ VL v22, 0(R1)		use v22 to test decoder
000015C4	E310 5014 0014	00000014		811+ LGF R1, V3ADDR		load v3 source
000015CA	E771 0000 0806	00000000		812+ VL v23, 0(R1)		use v23 to test decoder
000015D0	E766 7000 0EFE			813+ VMN V22, V22, V23, 0		test instruction (dest is a source)
000015D6	E760 5028 080E	000015A0		814+ VST V22, V109		save v1 output
000015DC	07FB			815+ BR R11		return
000015E0				816+RE9 DC OF		xl16 expected result
000015E0	01020304 0080FF80			817+ DROP R5		
000015E0	010AFED 0000001F			818 DC XL16' 010203040080FF80010AFED0000001F'		expected result

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000015F0	01020304 09800181			819	DC	XL16' 0102030409800181070FFFFD0000001F' v2
000015F8	070FFFFD 0000001F			820	DC	XL16' 020304050001FF80010AFEFE00000020' v3
00001600	02030405 0001FF80			821		
00001608	010AFEEF 00000020			822 * Halfword		
00001610		00001610		823 VRR_C VMN, 1		
00001610	00001650			824+ DS OFD		
00001614	000A			825+ USING *, R5		base for test data and test routine
00001616	00			826+T10 DC A(X10)		address of test routine
00001617	01			827+ DC H' 10'		test number
00001618	E5D4D540 40404040			828+ DC X' 00'		m4
00001620	00001688			829+ DC HL1' 1'		instruction name
00001624	00001698			830+ DC CL8' VMN'		address of v2 source
00001628	00000010			831+ DC A(RE10+16)		address of v3 source
0000162C	00001678			832+ DC A(RE10+32)		result length
00001630	00000000 00000000			833+ DC A(16)		result address
00001638	00000000 00000000			834+REA10 DC A(RE10)		gap
00001640	00000000 00000000			835+ DS FD		V1 output
00001648	00000000 00000000			836+V1010 DS XL16		
00001650				837+ DS FD		gap
00001650	838+*					
00001650	E310 5010 0014	00000010		839+X10 DS OF		
00001656	E761 0000 0806	00000000		840+ LGF R1, V2ADDR		load v2 source
0000165C	E310 5014 0014	00000014		841+ VL v22, 0(R1)		use v22 to test decoder
00001662	E771 0000 0806	00000000		842+ LGF R1, V3ADDR		load v3 source
00001668	E766 7000 1EFE			843+ VL v23, 0(R1)		use v23 to test decoder
0000166E	E760 5028 080E	00001638		844+ VMN V22, V22, V23, 1		test instruction (dest is a source)
00001674	07FB			845+ VST V22, V1010		save v1 output
00001678				846+ BR R11		return
00001678	0001FFFF FFFD8000			847+RE10 DC OF		xl16 expected result
00001680	00AA8000 0123001F			848+ DROP R5		
00001688	0001FFFF FFFD8000			849 DC XL16' 0001FFFFFFD800000AA80000123001F'		expected result
00001690	7FFF8000 0123001F			850 DC XL16' 0001FFFFFFD80007FFF80000123001F'		v2
00001698	00020001 FFFE0001			851 DC XL16' 00020001FFFE000100AA800112340020'		v3
000016A0	00AA8001 12340020			852		
000016A8		000016A8		853 * Word		
000016A8	000016E8			854 VRR_C VMN, 2		
000016AC	000B			855+ DS OFD		
000016AE	00			856+ USING *, R5		base for test data and test routine
000016AF	02			857+T11 DC A(X11)		address of test routine
000016B0	E5D4D540 40404040			858+ DC H' 11'		test number
000016B8	00001720			859+ DC X' 00'		m4
000016BC	00001730			860+ DC HL1' 2'		instruction name
000016C0	00000010			861+ DC CL8' VMN'		address of v2 source
000016C4	00001710			862+ DC A(RE11+16)		address of v3 source
000016C8	00000000 00000000			863+ DC A(RE11+32)		result length
000016D0	00000000 00000000			864+ DC A(16)		result address
000016D8	00000000 00000000			865+REA11 DC A(RE11)		gap
000016D8				866+ DS FD		V1 output
000016D8				867+V1011 DS XL16		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000016E0	00000000 00000000			868+ 869+*	DS	FD	gap
000016E8	E310 5010 0014		00000010	870+X11	DS	OF	
000016EE	E761 0000 0806		00000000	871+	LGF	R1, V2ADDR	load v2 source
000016F4	E310 5014 0014		00000014	872+	VL	v22, 0(R1)	use v22 to test decoder
000016FA	E771 0000 0806		00000000	873+	LGF	R1, V3ADDR	load v3 source
00001700	E766 7000 2EFE			874+	VL	v23, 0(R1)	use v23 to test decoder
00001706	E760 5028 080E		000016D0	875+	VMN	V22, V22, V23, 2	test instruction (dest is a source)
0000170C	07FB			876+	VST	V22, V1011	save v1 output
00001710				877+	BR	R11	return
00001710				878+RE11	DC	OF	xl16 expected result
00001710	FFFFFFE 0000000A			879+	DROP	R5	
00001718	01234567 0000001F			880	DC	XL16' FFFFFFFE0000000A012345670000001F'	expected result
00001720	FFFFFFF 7FFFFFF			881	DC	XL16' FFFFFFF7FFFFFF012345670000001F'	v2
00001728	01234567 0000001F			882	DC	XL16' FFFFFFFE0000000A1234567800000020'	v3
00001738	12345678 00000020			883			
				884 * Doubl eword			
00001740				885	VRR_C	VMN, 3	
00001740		00001740		886+	DS	OFD	
00001740	00001780			887+	USING	* , R5	base for test data and test routine
00001744	000C			888+T12	DC	A(X12)	address of test routine
00001746	00			889+	DC	H' 12'	test number
00001747	03			890+	DC	X' 00'	
00001748	E5D4D540 40404040			891+	DC	HL1' 3'	m4
00001750	000017B8			892+	DC	CL8' VMN'	instruction name
00001754	000017C8			893+	DC	A(RE12+16)	address of v2 source
00001758	00000010			894+	DC	A(RE12+32)	address of v3 source
0000175C	000017A8			895+	DC	A(16)	result length
00001760	00000000 00000000			896+REA12	DC	A(RE12)	result address
00001768	00000000 00000000			897+	DS	FD	gap
00001770	00000000 00000000			898+V1012	DS	XL16	V1 output
00001778	00000000 00000000			899+	DS	FD	gap
00001780				900+*			
00001780	E310 5010 0014		00000010	901+X12	DS	OF	
00001786	E761 0000 0806		00000000	902+	LGF	R1, V2ADDR	load v2 source
0000178C	E310 5014 0014		00000014	903+	VL	v22, 0(R1)	use v22 to test decoder
00001792	E771 0000 0806		00000000	904+	LGF	R1, V3ADDR	load v3 source
00001798	E766 7000 3EFE			905+	VL	v23, 0(R1)	use v23 to test decoder
0000179E	E760 5028 080E		00001768	906+	VMN	V22, V22, V23, 3	test instruction (dest is a source)
000017A4	07FB			907+	VST	V22, V1012	save v1 output
000017A8				908+	BR	R11	return
000017A8				909+RE12	DC	OF	xl16 expected result
000017A8	FFFFFFF FFFFFFFD			910+	DROP	R5	
000017B0	00000000 0000001F			911	DC	XL16' FFFFFFFFFFFFFD00000000000000001F'	expected result
000017B8	FFFFFFF FFFFFFFF			912	DC	XL16' FFFFFFFFFFFFFF00000000000000001F'	v2
000017C0	00000000 0000001F			913	DC	XL16' FFFFFFFFFFFFFD000000000000000020'	v3
000017C8	FFFFFFF FFFFFFFD			914			
000017D0	00000000 00000020			915 *			
				916 * VMNL	-	VECTOR MINIMUM LOGICAL	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				917 *-----	
				918 * Byte	
000017D8				919 VRR_C VMNL, 0	
000017D8		000017D8		920+ DS OFD	
000017D8	00001818			921+ USING *, R5	base for test data and test routine
000017DC	000D				address of test routine
000017DE	00			924+ DC X'00'	test number
000017DF	00			925+ DC HL1'0'	m4
000017E0	E5D4D5D3 40404040			926+ DC CL8' VMNL'	instruction name
000017E8	00001850			927+ DC A(RE13+16)	address of v2 source
000017EC	00001860			928+ DC A(RE13+32)	address of v3 source
000017F0	00000010			929+ DC A(16)	result length
000017F4	00001840			930+ REA13 DC A(RE13)	result address
000017F8	00000000 00000000			931+ DS FD	gap
00001800	00000000 00000000			932+ V1013 DS XL16	V1 output
00001808	00000000 00000000				
00001810	00000000 00000000			933+ DS FD	gap
00001818				934+*	
00001818	E310 5010 0014	00000010		935+ X13 DS OF	
0000181E	E761 0000 0806	00000000		936+ LGF R1, V2ADDR	load v2 source
00001824	E310 5014 0014	00000014		937+ VL v22, 0(R1)	use v22 to test decoder
0000182A	E771 0000 0806	00000000		938+ LGF R1, V3ADDR	load v3 source
00001830	E766 7000 0EFC			939+ VL v23, 0(R1)	use v23 to test decoder
00001836	E760 5028 080E	00001800		940+ VMNL V22, V22, V23, 0	test instruction (dest is a source)
0000183C	07FB			941+ VST V22, V1013	save v1 output
00001840				942+ BR R11	return
00001840				943+ RE13 DC OF	xl16 expected result
00001840				944+ DROP R5	
00001848	01020304 00010180			945 DC XL16' 0102030400010180010AFEFD0000001F'	expected result
00001850	010AFEFD 0000001F			946 DC XL16' 0102030409800181070FFFFD0000001F'	v2
00001858	01020304 09800181			947 DC XL16' 020304050001FF80010AFEFE00000020'	v3
00001860	070FFFFD 0000001F				
00001860	02030405 0001FF80				
00001868	02030405 0001FF80				
00001870	010AFEFE 00000020				
				948	
				949 * Halfword	
				950 VRR_C VMNL, 1	
00001870		00001870		951+ DS OFD	
00001870	000018B0			952+ USING *, R5	base for test data and test routine
00001874	000E			953+ T14 DC A(X14)	address of test routine
00001876	00			954+ DC H'14'	test number
00001877	01			955+ DC X'00'	
00001878	E5D4D5D3 40404040			956+ DC HL1'1'	m4
00001880	000018E8			957+ DC CL8' VMNL'	instruction name
00001884	000018F8			958+ DC A(RE14+16)	address of v2 source
00001888	00000010			959+ DC A(RE14+32)	address of v3 source
0000188C	000018D8			960+ DC A(16)	result length
00001890	00000000 00000000			961+ REA14 DC A(RE14)	result address
00001898	00000000 00000000			962+ DS FD	gap
000018A0	00000000 00000000			963+ V1014 DS XL16	V1 output
000018A8	00000000 00000000				
000018B0	00000000 00000000			964+ DS FD	gap
000018B0	E310 5010 0014	00000010		965+*	
000018B0				966+ X14 DS OF	
000018B0				967+ LGF R1, V2ADDR	load v2 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000018B6	E761 0000 0806		00000000	968+	VL	v22, 0(R1)	use v22 to test decoder
000018BC	E310 5014 0014		00000014	969+	LGF	R1, V3ADDR	load v3 source
000018C2	E771 0000 0806		00000000	970+	VL	v23, 0(R1)	use v23 to test decoder
000018C8	E766 7000 1EFC			971+	VMNL	V22, V22, V23, 1	test instruction (dest is a source)
000018CE	E760 5028 080E		00001898	972+	VST	V22, V1014	save v1 output
000018D4	07FB			973+	BR	R11	return
000018D8				974+RE14	DC	OF	xl16 expected result
000018D8				975+	DROP	R5	
000018D8	00010001 FFFD0001			976	DC	XL16' 00010001FFFD000100AA80000123001F'	expected result
000018E0	00AA8000 0123001F			977	DC	XL16' 0001FFFFFD80007FFF80000123001F'	v2
000018E8	0001FFFF FFFD8000			978	DC	XL16' 00020001FFFE000100AA800112340020'	v3
00001900	00AA8001 12340020			979			
				980 * Word			
				981	VRR_C	VMNL, 2	
00001908				982+	DS	OFD	
00001908	00001948	00001908		983+	USING	*, R5	base for test data and test routine
00001908				984+T15	DC	A(X15)	address of test routine
0000190C	000F			985+	DC	H' 15'	test number
0000190E	00			986+	DC	X' 00'	
0000190F	02			987+	DC	HL1' 2'	m4
00001910	E5D4D5D3 40404040			988+	DC	CL8' VMNL'	instruction name
00001918	00001980			989+	DC	A(RE15+16)	address of v2 source
0000191C	00001990			990+	DC	A(RE15+32)	address of v3 source
00001920	00000010			991+	DC	A(16)	result length
00001924	00001970			992+REA15	DC	A(RE15)	result address
00001928	00000000 00000000			993+	DS	FD	gap
00001930	00000000 00000000			994+V1015	DS	XL16	V1 output
00001938	00000000 00000000			995+	DS	FD	gap
00001940	00000000 00000000			996+*			
00001948				997+X15	DS	OF	
00001948	E310 5010 0014		00000010	998+	LGF	R1, V2ADDR	load v2 source
0000194E	E761 0000 0806		00000000	999+	VL	v22, 0(R1)	use v22 to test decoder
00001954	E310 5014 0014		00000014	1000+	LGF	R1, V3ADDR	load v3 source
0000195A	E771 0000 0806		00000000	1001+	VL	v23, 0(R1)	use v23 to test decoder
00001960	E766 7000 2EFC			1002+	VMNL	V22, V22, V23, 2	test instruction (dest is a source)
00001966	E760 5028 080E		00001930	1003+	VST	V22, V1015	save v1 output
0000196C	07FB			1004+	BR	R11	return
00001970				1005+RE15	DC	OF	xl16 expected result
00001970				1006+	DROP	R5	
00001970	FFFFFFFFFF 0000000A			1007	DC	XL16' FFFFFFFF012345670000001F'	expected result
00001978	01234567 0000001F			1008	DC	XL16' FFFFFFFF012345670000001F'	v2
00001980	FFFFFFFFFF 7FFFFFFF			1009	DC	XL16' FFFFFFFF01234567800000020'	v3
00001988	01234567 0000001F			1010			
00001990	FFFFFFFFFF 0000000A			1011 * Doubleword			
00001998	12345678 00000020			1012	VRR_C	VMNL, 3	
000019A0				1013+	DS	OFD	
000019A0	000019E0	000019A0		1014+	USING	*, R5	base for test data and test routine
000019A0	0010			1015+T16	DC	A(X16)	address of test routine
000019A4				1016+	DC	H' 16'	test number

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000019A6	00			1017+ DC X' 00'		
000019A7	03			1018+ DC HL1' 3'	m4	
000019A8	E5D4D5D3 40404040			1019+ DC CL8' VMNL'	instruction name	
000019B0	00001A18			1020+ DC A(RE16+16)	address of v2 source	
000019B4	00001A28			1021+ DC A(RE16+32)	address of v3 source	
000019B8	00000010			1022+ DC A(16)	result length	
000019BC	00001A08			1023+REA16 DC A(RE16)	result address	
000019C0	00000000 00000000			1024+ DS FD	gap	
000019C8	00000000 00000000			1025+V1016 DS XL16	V1 output	
000019D0	00000000 00000000			1026+ DS FD	gap	
000019D8	00000000 00000000			1027+*		
000019E0				1028+X16 DS OF		
000019E0	E310 5010 0014	00000010		1029+ LGF R1, V2ADDR	load v2 source	
000019E6	E761 0000 0806	00000000		1030+ VL v22, 0(R1)	use v22 to test decoder	
000019EC	E310 5014 0014	00000014		1031+ LGF R1, V3ADDR	load v3 source	
000019F2	E771 0000 0806	00000000		1032+ VL v23, 0(R1)	use v23 to test decoder	
000019F8	E766 7000 3EFC			1033+ VMNL V22, V22, V23, 3	test instruction (dest is a source)	
000019FE	E760 5028 080E	000019C8		1034+ VST V22, V1016	save v1 output	
00001A04	07FB			1035+ BR R11	return	
00001A08				1036+RE16 DC OF	xl16 expected result	
00001A08				1037+ DROP R5		
00001A08	FFFFFF FFFFFFFD			1038 DC XL16' FFFFFFFFFFFFFD0000000000000001F'	expected result	
00001A10	00000000 0000001F					
00001A18	FFFFFF FFFFFFFF			1039 DC XL16' FFFFFFFFFFFFFF0000000000000001F'	v2	
00001A20	00000000 0000001F					
00001A28	FFFFFF FFFFFFFD			1040 DC XL16' FFFFFFFFFFFFFD00000000000000020'	v3	
00001A30	00000000 00000020					
00001A38				1041		
00001A38				1042 *-----		
00001A38	00001A78	00001A38		1043 * VAVG - VECTOR AVERAGE		
00001A3C	0011			1044 *-----		
00001A3E	00			1045 * Byte		
00001A3F	00					
00001A40	E5C1E5C7 40404040			1046 VRR_C VAVG, 0		
00001A48	00001AB0			1047+ DS OFD		
00001A4C	00001AC0			1048+ USING *, R5	base for test data and test routine	
00001A50	00000010			1049+T17 DC A(X17)	address of test routine	
00001A54	00001AA0			1050+ DC H' 17'	test number	
00001A58	00000000 00000000			1051+ DC X' 00'	m4	
00001A60	00000000 00000000			1052+ DC HL1' 0'	instruction name	
00001A68	00000000 00000000			1053+ DC CL8' VAVG'	address of v2 source	
00001A70	00000000 00000000			1054+ DC A(RE17+16)	address of v3 source	
00001A78				1055+ DC A(RE17+32)	result length	
00001A78	E310 5010 0014	00000010		1056+ DC A(16)	result address	
00001A7E	E761 0000 0806	00000000		1057+REA17 DC A(RE17)	gap	
00001A84	E310 5014 0014	00000014		1058+ DS FD	V1 output	
00001A8A	E771 0000 0806	00000000		1059+V1017 DS XL16	gap	
00001A90	E766 7000 0EF2			1060+ DS FD		
				1061+*		
				1062+X17 DS OF		
				1063+ LGF R1, V2ADDR	load v2 source	
				1064+ VL v22, 0(R1)	use v22 to test decoder	
				1065+ LGF R1, V3ADDR	load v3 source	
				1066+ VL v23, 0(R1)	use v23 to test decoder	
				1067+ VAVG V22, V22, V23, 0	test instruction (dest is a source)	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001B7C	00001BF0			1117+ DC A(RE19+32)	address of v3 source	
00001B80	00000010			1118+ DC A(16)	result length	
00001B84	00001BD0			1119+REA19 DC A(RE19)	result address	
00001B88	00000000 00000000			1120+ DS FD	gap	
00001B90	00000000 00000000			1121+V1019 DS XL16	V1 output	
00001B98	00000000 00000000			1122+ DS FD	gap	
00001BA0	00000000 00000000			1123+*		
00001BA8				1124+X19 DS OF		
00001BA8	E310 5010 0014	00000010		1125+ LGF R1, V2ADDR	load v2 source	
00001BAE	E761 0000 0806	00000000		1126+ VL v22, 0(R1)	use v22 to test decoder	
00001BB4	E310 5014 0014	00000014		1127+ LGF R1, V3ADDR	load v3 source	
00001BBA	E771 0000 0806	00000000		1128+ VL v23, 0(R1)	use v23 to test decoder	
00001BC0	E766 7000 2EF2			1129+ VAVG V22, V22, V23, 2	test instruction (dest is a source)	
00001BC6	E760 5028 080E	00001B90		1130+ VST V22, V1019	save v1 output	
00001BCC	07FB			1131+ BR R11	return	
00001BDO				1132+RE19 DC OF	xl16 expected result	
00001BDO	FF7F7F7F FF7F7F7F			1133+ DROP R5		
00001BD8	FF7F7F7F FF7F7F7F			1134 DC XL16' FF7F7F7FFF7F7F7FFF7F7F7FFF7F7F7F'	expected result	
00001BE0	7C7C7C7C 7C7C7C7C			1135 DC XL16' 7C7C7C7C7C7C7C7C7C7C7C7C7C7C7C7C'	v2	
00001BE8	7C7C7C7C 7C7C7C7C			1136 DC XL16' 82828282828282828282828282828282'	v3	
00001BF8	82828282 82828282			1137		
				1138 * Doubleword		
00001C00		00001C00		1139 VRR_C VAVG, 3		
00001C00	00001C40			1140+ DS OFD		
00001C04	0014			1141+ USING *, R5	base for test data and test routine	
00001C06	00			1142+T20 DC A(X20)	address of test routine	
00001C07	03			1143+ DC H' 20'	test number	
00001C08	E5C1E5C7 40404040			1144+ DC X' 00'		
00001C10	00001C78			1145+ DC HL1' 3'	m4	
00001C14	00001C88			1146+ DC CL8' VAVG'	instruction name	
00001C18	00000010			1147+ DC A(RE20+16)	address of v2 source	
00001C1C	00001C68			1148+ DC A(RE20+32)	address of v3 source	
00001C20	00000000 00000000			1149+ DC A(16)	result length	
00001C28	00000000 00000000			1150+REA20 DC A(RE20)	result address	
00001C30	00000000 00000000			1151+ DS FD	gap	
00001C38	00000000 00000000			1152+V1020 DS XL16	V1 output	
00001C38	00000000 00000000			1153+ DS FD	gap	
00001C40				1154+*		
00001C40	E310 5010 0014	00000010		1155+X20 DS OF		
00001C46	E761 0000 0806	00000000		1156+ LGF R1, V2ADDR	load v2 source	
00001C4C	E310 5014 0014	00000014		1157+ VL v22, 0(R1)	use v22 to test decoder	
00001C52	E771 0000 0806	00000000		1158+ LGF R1, V3ADDR	load v3 source	
00001C58	E766 7000 3EF2			1159+ VL v23, 0(R1)	use v23 to test decoder	
00001C5E	E760 5028 080E	00001C28		1160+ VAVG V22, V22, V23, 3	test instruction (dest is a source)	
00001C64	07FB			1161+ VST V22, V1020	save v1 output	
00001C68				1162+ BR R11	return	
00001C68				1163+RE20 DC OF	xl16 expected result	
00001C68				1164+ DROP R5		
00001C68	FF7F7F7F 7F7F7F7F			1165 DC XL16' FF7F7F7F7F7FFF7F7F7FFF7F7F7F'	expected result	
00001C70	FF7F7F7F 7F7F7F7F			1166 DC XL16' 7C7C7C7C7C7C7C7C7C7C7C7C7C7C7C'	v2	
00001C78	7C7C7C7C 7C7C7C7C					

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001D70				1216+*			
00001D70	E310 5010 0014	00000010	1218+	LGF R1, V2ADDR	load v2 source		
00001D76	E761 0000 0806	00000000	1219+	VL v22, 0(R1)	use v22 to test decoder		
00001D7C	E310 5014 0014	00000014	1220+	LGF R1, V3ADDR	load v3 source		
00001D82	E771 0000 0806	00000000	1221+	VL v23, 0(R1)	use v23 to test decoder		
00001D88	E766 7000 3EF2		1222+	VAVG V22, V22, V23, 3	test instruction (dest is a source)		
00001D8E	E760 5028 080E	00001D58	1223+	VST V22, V1022	save v1 output		
00001D94	07FB		1224+	BR R11	return		
00001D98			1225+RE22	DC OF	xl16 expected result		
00001D98			1226+	DROP R5			
00001D98	FFFFFFF FFFFFFFF		1227	DC XL16' FFFFFFFFFFFFFFFFFFFFFFFFF'	expected result		
00001DAO	FFFFFFF FFFFFFFF		1228	DC XL16' 80000000000000028000000000000002'	v2		
00001DA8	80000000 00000002		1229	DC XL16' 7FFFFFFFC7FFFFFFFC'	v3		
00001DC0	80000000 00000002						
00001DC0	7FFFFFF FFFFFFFC						
00001DC0	7FFFFFF FFFFFFFC						
00001DC8			1230				
00001DC8			1231 * Doubl eword				
00001DC8	00001E08	00001DC8	1232	VRR_C VAVG, 3			
00001DC8	0017		1233+	DS OFD			
00001DCE	00		1234+	USING *, R5	base for test data and test routine		
00001DCF	03		1235+T23	DC A(X23)	address of test routine		
00001DD0	E5C1E5C7 40404040		1236+	DC H' 23'	test number		
00001DD8	00001E40		1237+	DC X' 00'			
00001DDC	00001E50		1238+	DC HL1' 3'	m4		
00001DE0	00000010		1239+	DC CL8' VAVG'	instruction name		
00001DE4	00001E30		1240+	DC A(RE23+16)	address of v2 source		
00001DE8	00000000 00000000		1241+	DC A(RE23+32)	address of v3 source		
00001DF0	00000000 00000000		1242+	DC A(16)	result length		
00001DF8	00000000 00000000		1243+REA23	DC A(RE23)	result address		
00001E00	00000000 00000000		1244+	DS FD	gap		
00001E00	00000000 00000000		1245+V1023	DS XL16	V1 output		
00001E00	00000000 00000000		1246+	DS FD	gap		
00001E08			1247+*				
00001E08	E310 5010 0014	00000010	1248+X23	DS OF			
00001E0E	E761 0000 0806	00000000	1249+	LGF R1, V2ADDR	load v2 source		
00001E14	E310 5014 0014	00000014	1250+	VL v22, 0(R1)	use v22 to test decoder		
00001E1A	E771 0000 0806	00000000	1251+	LGF R1, V3ADDR	load v3 source		
00001E20	E766 7000 3EF2		1252+	VL v23, 0(R1)	use v23 to test decoder		
00001E26	E760 5028 080E	00001DF0	1253+	VAVG V22, V22, V23, 3	test instruction (dest is a source)		
00001E2C	07FB		1254+	VST V22, V1023	save v1 output		
00001E2C	07FB		1255+	BR R11	return		
00001E30			1256+RE23	DC OF	xl16 expected result		
00001E30			1257+	DROP R5			
00001E30	FFFFFFF FFFFFFFF		1258	DC XL16' FFFFFFFFFFFFFFFFFFF'	expected result		
00001E38	FFFFFFF FFFFFFFF		1259	DC XL16' 7FFFFFFFC7FFFFFFFC'	v2		
00001E40	7FFFFFF FFFFFFFC		1260	DC XL16' 80000000000000028000000000000002'	v3		
00001E48	7FFFFFF FFFFFFFC						
00001E50	80000000 00000002						
00001E58	80000000 00000002		1261				
00001E60			1262 * Doubl eword				
00001E60			1263	VRR_C VAVG, 3			
00001E60			1264+	DS OFD			

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001E60		00001E60		1265+ USING *, R5 1266+T24 DC A(X24)	base for test data and test routine	
00001E60	00001EA0			1267+ DC H'24' 1268+ DC X'00' 1269+ DC HL1'3'	address of test routine	
00001E64	0018				test number	
00001E66	00				m4	
00001E67	03					
00001E68	E5C1E5C7 40404040			1270+ DC CL8' VAVG' 1271+ DC A(RE24+16) 1272+ DC A(RE24+32)	instruction name	
00001E70	00001ED8			1273+ DC A(16)	address of v2 source	
00001E74	00001EE8			1274+REA24 DC A(RE24)	address of v3 source	
00001E78	00000010			1275+ DS FD	result length	
00001E7C	00001EC8			1276+V1024 DS XL16	result address	
00001E80	00000000 00000000			1277+ DS FD	gap	
00001E88	00000000 00000000			1278+*	V1 output	
00001E90	00000000 00000000					
00001E98	00000000 00000000				gap	
00001EA0				1279+X24 DS OF		
00001EA0	E310 5010 0014	00000010		1280+ LGF R1, V2ADDR	load v2 source	
00001EA6	E761 0000 0806	00000000		1281+ VL v22, 0(R1)	use v22 to test decoder	
00001EAC	E310 5014 0014	00000014		1282+ LGF R1, V3ADDR	load v3 source	
00001EB2	E771 0000 0806	00000000		1283+ VL v23, 0(R1)	use v23 to test decoder	
00001EB8	E766 7000 3EF2			1284+ VAVG V22, V22, V23, 3	test instruction (dest is a source)	
00001EBE	E760 5028 080E	00001E88		1285+ VST V22, V1024	save v1 output	
00001EC4	07FB			1286+ BR R11	return	
00001EC8				1287+RE24 DC OF	xl16 expected result	
00001EC8				1288+ DROP R5		
00001EC8	80000000 00000002			1289 DC XL16' 8000000000000000280000000000000002'	expected result	
00001ED0	80000000 00000002			1290 DC XL16' 8000000000000000280000000000000002'	v2	
00001ED8	80000000 00000002					
00001EE0	80000000 00000002			1291 DC XL16' 8000000000000000280000000000000002'	v3	
00001EE8	80000000 00000002			1292		
00001EF0	80000000 00000002			1293		
00001EF8				1294 *		
00001EF8	00001F38	00001EF8		1295 *VAVGL - VECTOR AVERAGE LOGICAL		
00001EF8	0019			1296 *		
00001EFE	00			1297 * Byte		
00001EFF	00			1298 VRR_C VAVGL, 0		
00001F00	E5C1E5C7 D3404040			1299+ DS OFD		
00001F08	00001F70			1300+ USING *, R5	base for test data and test routine	
00001FOC	00001F80			1301+T25 DC A(X25)	address of test routine	
00001F10	00000010			1302+ DC H'25'	test number	
00001F14	00001F60			1303+ DC X'00'	m4	
00001F18	00000000 00000000			1304+ DC HL1'0'		
00001F20	00000000 00000000			1305+ DC CL8' VAVGL'	instruction name	
00001F28	00000000 00000000			1306+ DC A(RE25+16)	address of v2 source	
00001F30	00000000 00000000			1307+ DC A(RE25+32)	address of v3 source	
00001F38				1308+ DC A(16)	result length	
00001F38	E310 5010 0014	00000010		1309+REA25 DC A(RE25)	result address	
00001F38				1310+ DS FD	gap	
00001F38				1311+V1025 DS XL16	V1 output	
00001F38				1312+ DS FD	gap	
00001F38				1313+*		
00001F38				1314+X25 DS OF		
00001F38				1315+ LGF R1, V2ADDR	load v2 source	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001F3E	E761 0000 0806		00000000	1316+ VL v22, 0(R1)		use v22 to test decoder
00001F44	E310 5014 0014		00000014	1317+ LGF R1, V3ADDR		load v3 source
00001F4A	E771 0000 0806		00000000	1318+ VL v23, 0(R1)		use v23 to test decoder
00001F50	E766 7000 0EF0		1319+	VAVGL V22, V22, V23, 0		test instruction (dest is a source)
00001F56	E760 5028 080E		00001F20	1320+ VST V22, V1025		save v1 output
00001F5C	07FB			1321+ BR R11		return
00001F60				1322+RE25 DC OF		xl16 expected result
00001F60				1323+ DROP R5		
00001F60	7F7F7F7F 7F7F7F7F			1324 DC XL16' 7F7F7F7F7F7F7F7F7F7F7F7F7F7F7F7F'		expected result
00001F68	7F7F7F7F 7F7F7F7F			1325 DC XL16' 7C7C7C7C7C7C7C7C7C7C7C7C7C7C7C7C'		v2
00001F70	7C7C7C7C 7C7C7C7C			1326 DC XL16' 82828282828282828282828282828282'		v3
00001F78	7C7C7C7C 7C7C7C7C					
00001F80	82828282 82828282					
00001F88	82828282 82828282					
				1327		
				1328 * Halfword		
				1329 VRR_C VAVGL, 1		
00001F90				1330+ DS OFD		
00001F90				1331+ USING *, R5		base for test data and test routine
00001F90	00001FD0	00001F90		1332+T26 DC A(X26)		address of test routine
00001F94	001A			1333+ DC H' 26'		test number
00001F96	00			1334+ DC X' 00'		
00001F97	01			1335+ DC HL1' 1'		m4
00001F98	E5C1E5C7 D3404040			1336+ DC CL8' VAVGL'		instruction name
00001FA0	00002008			1337+ DC A(RE26+16)		address of v2 source
00001FA4	00002018			1338+ DC A(RE26+32)		address of v3 source
00001FA8	00000010			1339+ DC A(16)		result length
00001FAC	00001FF8			1340+RE26 DC A(RE26)		result address
00001FB0	00000000 00000000			1341+ DS FD		gap
00001FB8	00000000 00000000			1342+V1026 DS XL16		V1 output
00001FC0	00000000 00000000					
00001FC8	00000000 00000000			1343+ DS FD		gap
				1344+*		
				1345+X26 DS OF		
00001FD0	E310 5010 0014		00000010	1346+ LGF R1, V2ADDR		load v2 source
00001FD6	E761 0000 0806		00000000	1347+ VL v22, 0(R1)		use v22 to test decoder
00001FDC	E310 5014 0014		00000014	1348+ LGF R1, V3ADDR		load v3 source
00001FE2	E771 0000 0806		00000000	1349+ VL v23, 0(R1)		use v23 to test decoder
00001FE8	E766 7000 1EF0			1350+ VAVGL V22, V22, V23, 1		test instruction (dest is a source)
00001FEE	E760 5028 080E		00001FB8	1351+ VST V22, V1026		save v1 output
00001FF4	07FB			1352+ BR R11		return
00001FF8				1353+RE26 DC OF		xl16 expected result
00001FF8				1354+ DROP R5		
00001FF8	7F7F7F7F 7F7F7F7F			1355 DC XL16' 7F7F7F7F7F7F7F7F7F7F7F7F7F7F7F7F'		expected result
00002000	7F7F7F7F 7F7F7F7F					
00002008	7C7C7C7C 7C7C7C7C			1356 DC XL16' 7C7C7C7C7C7C7C7C7C7C7C7C7C7C7C7C'		v2
00002010	7C7C7C7C 7C7C7C7C					
00002018	82828282 82828282			1357 DC XL16' 82828282828282828282828282828282'		v3
00002020	82828282 82828282					
				1358		
				1359 * Word		
				1360 VRR_C VAVGL, 2		
00002028				1361+ DS OFD		
00002028				1362+ USING *, R5		base for test data and test routine
00002028	00002068	00002028		1363+T27 DC A(X27)		address of test routine
0000202C	001B			1364+ DC H' 27'		test number

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00002210	00000000 00000000			1465+	DS	FD
00002218	00000000 00000000			1466+V1030	DS	XL16
00002220	00000000 00000000					gap
00002228	00000000 00000000			1467+	DS	FD
				1468+*		gap
00002230				1469+X30	DS	OF
00002230	E310 5010 0014	00000010		1470+	LGF	R1, V2ADDR
00002236	E761 0000 0806	00000000		1471+	VL	v22, 0(R1)
0000223C	E310 5014 0014	00000014		1472+	LGF	R1, V3ADDR
00002242	E771 0000 0806	00000000		1473+	VL	v23, 0(R1)
00002248	E766 7000 3EF0			1474+	VAVGL	V22, V22, V23, 3
0000224E	E760 A018 080E	00002218		1475+	VST	V22, V1030
00002254	07FB			1476+	BR	R11
00002258				1477+RE30	DC	OF
00002258	7FFFFFFF FFFFFFFF			1478+	DROP	R5
00002258	7FFFFFFF FFFFFFFF			1479	DC	XL16' 7FFFFFFFFFFFFF7FFFFFFFFFFFF'
00002260	7FFFFFFF FFFFFFFF					expected result
00002268	80000000 00000002			1480	DC	XL16' 80000000000000028000000000000002'
00002270	80000000 00000002					v2
00002278	7FFFFFFF FFFFFFFC			1481	DC	XL16' 7FFFFFFFFF7FFFFFFFFF7FFFFFFFFF'
00002280	7FFFFFFF FFFFFFFC					v3
				1482		
				1483 * Doubl eword		
00002288		00002288		1484	VRR_C	VAVGL, 3
00002288				1485+	DS	OFD
00002288	000022C8			1486+	USING	* , R5
0000228C	001F			1487+T31	DC	A(X31)
0000228E	00			1488+	DC	H' 31'
0000228F	03			1489+	DC	X' 00'
00002290	E5C1E5C7 D3404040			1490+	DC	HL1' 3'
00002298	00002300			1491+	DC	CL8' VAVGL'
0000229C	00002310			1492+	DC	A(RE31+16)
000022A0	00000010			1493+	DC	A(RE31+32)
000022A4	000022F0			1494+	DC	A(16)
000022A8	00000000 00000000			1495+REA31	DC	A(RE31)
000022B0	00000000 00000000			1496+	DS	FD
000022B8	00000000 00000000			1497+V1031	DS	XL16
000022C0	00000000 00000000					gap
000022C8				1498+	DS	FD
				1499+*		gap
				1500+X31	DS	OF
000022C8	E310 5010 0014	00000010		1501+	LGF	R1, V2ADDR
000022CE	E761 0000 0806	00000000		1502+	VL	v22, 0(R1)
000022D4	E310 5014 0014	00000014		1503+	LGF	R1, V3ADDR
000022DA	E771 0000 0806	00000000		1504+	VL	v23, 0(R1)
000022E0	E766 7000 3EF0			1505+	VAVGL	V22, V22, V23, 3
000022E6	E760 5028 080E	000022B0		1506+	VST	V22, V1031
000022EC	07FB			1507+	BR	R11
000022F0				1508+RE31	DC	OF
000022F0				1509+	DROP	R5
000022F0	7FFFFFFF FFFFFFFF			1510	DC	XL16' 7FFFFFFFFFFFFF7FFFFFFFFFFFF'
000022F8	7FFFFFFF FFFFFFFF					expected result
00002300	7FFFFFFF FFFFFFFC			1511	DC	XL16' 7FFFFFFFFF7FFFFFFFFF7FFFFFFFFF'
00002308	7FFFFFFF FFFFFFFC					v2
00002310	80000000 00000002			1512	DC	XL16' 80000000000000028000000000000002'
00002318	80000000 00000002					v3

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				1513	
				1514 * Doubleword	
00002320				1515 VRR_C VAVGL, 3	
00002320		00002320		1516+ DS OFD	
				1517+ USING *, R5	base for test data and test routine
00002320	00002360			1518+T32 DC A(X32)	address of test routine
00002324	0020			1519+ DC H'32'	test number
00002326	00			1520+ DC X'00'	
00002327	03			1521+ DC HL1'3'	m4
00002328	E5C1E5C7 D3404040			1522+ DC CL8'VAVGL'	instruction name
00002330	00002398			1523+ DC A(RES2+16)	address of v2 source
00002334	000023A8			1524+ DC A(RES2+32)	address of v3 source
00002338	00000010			1525+ DC A(16)	result length
0000233C	00002388			1526+REA32 DC A(RES2)	result address
00002340	00000000 00000000			1527+ DS FD	gap
00002348	00000000 00000000			1528+V1032 DS XL16	V1 output
00002350	00000000 00000000				
00002358	00000000 00000000			1529+ DS FD	gap
00002360				1530+* DS OF	
				1531+X32 DS OF	
00002360	E310 5010 0014	00000010		1532+ LGF R1, V2ADDR	load v2 source
00002366	E761 0000 0806	00000000		1533+ VL v22, 0(R1)	use v22 to test decoder
0000236C	E310 5014 0014	00000014		1534+ LGF R1, V3ADDR	load v3 source
00002372	E771 0000 0806	00000000		1535+ VL v23, 0(R1)	use v23 to test decoder
00002378	E766 7000 3EF0			1536+ VAVGL V22, V22, V23, 3	test instruction (dest is a source)
0000237E	E760 5028 080E	00002348		1537+ VST V22, V1032	save v1 output
00002384	07FB			1538+ BR R11	return
00002388				1539+RE32 DC OF	xl16 expected result
00002388				1540+ DROP R5	
00002388	80000000 00000002			1541 DC XL16' 8000000000000000280000000000000002'	expected result
00002390	80000000 00000002			1542 DC XL16' 8000000000000000280000000000000002'	v2
00002398	80000000 00000002			1543 DC XL16' 8000000000000000280000000000000002'	v3
000023A0	80000000 00000002				
000023A8	80000000 00000002				
000023B0	80000000 00000002				
				1544	
				1545	
000023B8	00000000			1546 DC F'0'	END OF TABLE
000023BC	00000000			1547 DC F'0'	
				1548 *	
				1549 * table of pointers to individual load test	
				1550 *	
000023C0				1551 E7TESTS DS OF	
				1552 PTTABLE	
000023C0				1553+TTABLE DS OF	
000023C0	000010B8			1554+ DC A(T1)	TEST &CUR
000023C4	00001150			1555+ DC A(T2)	TEST &CUR
000023C8	000011E8			1556+ DC A(T3)	TEST &CUR
000023CC	00001280			1557+ DC A(T4)	TEST &CUR
000023D0	00001318			1558+ DC A(T5)	TEST &CUR
000023D4	000013B0			1559+ DC A(T6)	TEST &CUR
000023D8	00001448			1560+ DC A(T7)	TEST &CUR
000023DC	000014E0			1561+ DC A(T8)	TEST &CUR
000023E0	00001578			1562+ DC A(T9)	TEST &CUR
000023E4	00001610			1563+ DC A(T10)	TEST &CUR
000023E8	000016A8			1564+ DC A(T11)	TEST &CUR

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
000023EC	00001740		1565+	DC A(T12)	TEST &CUR
000023F0	000017D8		1566+	DC A(T13)	TEST &CUR
000023F4	00001870		1567+	DC A(T14)	TEST &CUR
000023F8	00001908		1568+	DC A(T15)	TEST &CUR
000023FC	000019A0		1569+	DC A(T16)	TEST &CUR
00002400	00001A38		1570+	DC A(T17)	TEST &CUR
00002404	00001AD0		1571+	DC A(T18)	TEST &CUR
00002408	00001B68		1572+	DC A(T19)	TEST &CUR
0000240C	00001C00		1573+	DC A(T20)	TEST &CUR
00002410	00001C98		1574+	DC A(T21)	TEST &CUR
00002414	00001D30		1575+	DC A(T22)	TEST &CUR
00002418	00001DC8		1576+	DC A(T23)	TEST &CUR
0000241C	00001E60		1577+	DC A(T24)	TEST &CUR
00002420	00001EF8		1578+	DC A(T25)	TEST &CUR
00002424	00001F90		1579+	DC A(T26)	TEST &CUR
00002428	00002028		1580+	DC A(T27)	TEST &CUR
0000242C	000020C0		1581+	DC A(T28)	TEST &CUR
00002430	00002158		1582+	DC A(T29)	TEST &CUR
00002434	000021F0		1583+	DC A(T30)	TEST &CUR
00002438	00002288		1584+	DC A(T31)	TEST &CUR
0000243C	00002320		1585+	DC A(T32)	TEST &CUR
			1586+*		
00002440	00000000		1587+	DC A(0)	END OF TABLE
00002444	00000000		1588+	DC A(0)	
			1589		
00002448	00000000		1590	DC F' 0'	END OF TABLE
0000244C	00000000		1591	DC F' 0'	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				1593 **** Register equates
				1594 * Register equates
				1595 ****
	00000000	00000001	1597	R0 EQU 0
	00000001	00000001	1598	R1 EQU 1
	00000002	00000001	1599	R2 EQU 2
	00000003	00000001	1600	R3 EQU 3
	00000004	00000001	1601	R4 EQU 4
	00000005	00000001	1602	R5 EQU 5
	00000006	00000001	1603	R6 EQU 6
	00000007	00000001	1604	R7 EQU 7
	00000008	00000001	1605	R8 EQU 8
	00000009	00000001	1606	R9 EQU 9
	0000000A	00000001	1607	R10 EQU 10
	0000000B	00000001	1608	R11 EQU 11
	0000000C	00000001	1609	R12 EQU 12
	0000000D	00000001	1610	R13 EQU 13
	0000000E	00000001	1611	R14 EQU 14
	0000000F	00000001	1612	R15 EQU 15
				1614 ****
				1615 * Register equates
				1616 ****
	00000000	00000001	1618	V0 EQU 0
	00000001	00000001	1619	V1 EQU 1
	00000002	00000001	1620	V2 EQU 2
	00000003	00000001	1621	V3 EQU 3
	00000004	00000001	1622	V4 EQU 4
	00000005	00000001	1623	V5 EQU 5
	00000006	00000001	1624	V6 EQU 6
	00000007	00000001	1625	V7 EQU 7
	00000008	00000001	1626	V8 EQU 8
	00000009	00000001	1627	V9 EQU 9
	0000000A	00000001	1628	V10 EQU 10
	0000000B	00000001	1629	V11 EQU 11
	0000000C	00000001	1630	V12 EQU 12
	0000000D	00000001	1631	V13 EQU 13
	0000000E	00000001	1632	V14 EQU 14
	0000000F	00000001	1633	V15 EQU 15
	00000010	00000001	1634	V16 EQU 16
	00000011	00000001	1635	V17 EQU 17
	00000012	00000001	1636	V18 EQU 18
	00000013	00000001	1637	V19 EQU 19
	00000014	00000001	1638	V20 EQU 20
	00000015	00000001	1639	V21 EQU 21

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
		00000016	00000001	1640 V22
		00000017	00000001	EQU 22
		00000018	00000001	1641 V23
		00000019	00000001	EQU 23
		0000001A	00000001	1642 V24
		0000001B	00000001	EQU 24
		0000001C	00000001	1643 V25
		0000001D	00000001	EQU 25
		0000001E	00000001	1644 V26
		0000001F	00000001	EQU 26
				1645 V27
				EQU 27
				1646 V28
				EQU 28
				1647 V29
				EQU 29
				1648 V30
				EQU 30
				1649 V31
				EQU 31
				1650
				1651 END

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES				
BEGIN	I	00000200	2	161	127	157	158	159	
CTLRO	F	0000048C	4	357	171	172	173	174	
DECNUM	C	00001073	16	408	271	273	279	281	
E7TEST	4	00000000	64	422	220				
E7TESTS	F	000023C0	4	1551	213				
EDIT	X	00001047	18	403	272	280			
ENDTEST	U	0000031E	1	257	218				
EOJ	I	00000470	4	347	206	260			
EOJPSW	D	00000460	8	345	347				
FAILCONT	U	0000030E	1	247					
FAILED	F	00001000	4	385	249	258			
FAILMSG	U	0000030A	1	241	231				
FAILPSW	D	00000478	8	349	351				
FAILTEST	I	00000488	4	351	261				
FB0001	F	00000280	8	190	194	195	197		
IMAGE	I	00000000	9296	0					
K	U	00000400	1	369	370	371	372		
K64	U	00010000	1	371					
M4	U	00000007	1	426	278				
MB	U	00100000	1	372					
MSG	I	000003A8	4	307	205	290			
MSGCMD	C	000003F6	9	337	320	321			
MSGMSG	C	000003FF	95	338	314	335	312		
MSGMVC	I	000003F0	6	335	318				
MSGOK	I	000003BE	2	316	313				
MSGRET	I	000003DE	4	331	324	327			
MSGSAVE	F	000003E4	4	334	310	331			
NEXTE6	U	000002D4	1	215	234	252			
OPNAME	C	00000008	8	428	276				
PAGE	U	00001000	1	370					
PRT3	C	0000105D	18	406	272	273	274	280	281
PRTLINE	C	00001008	16	391	398	289			282
PRTLNG	U	0000003F	1	398	288				
PRTM4	C	00001044	2	396	282				
PRTNAME	C	00001033	8	394	276				
PRTNUM	C	00001018	3	392	274				
R0	U	00000000	1	1597	121	171	174	194	196
					288	291	307	310	312
								314	316
								317	331
R1	U	00000001	1	1598	204	229	230	258	259
					587	588	589	617	618
								619	620
					684	685	713	714	715
								716	744
								745	746
									747
					778	809	810	811	812
					902	903	904	905	936
								937	938
					999	1000	1001	1029	1030
								1031	1032
								1063	1064
								1064	1065
								1065	1066
								1066	1094
									1095
					1096	1097	1125	1126	1127
								1128	1156
					1190	1218	1219	1220	1221
								1249	1250
					1315	1316	1317	1318	1346
								1347	1348
								1348	1349
								1349	1377
								1377	1378
								1378	1379
								1379	1380
									1408
R10	U	0000000A	1	1607	159	168	169		
R11	U	0000000B	1	1608	226	227	561	592	623
					908	942	973	1004	1035
								1069	1100
					1321	1352	1383	1414	1445
								1476	1507
									1538
R12	U	0000000C	1	1609	213	216	233	251	
R13	U	0000000D	1	1610					
R14	U	0000000E	1	1611					

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
REA18	A	00001AEC	4	1088	
REA19	A	00001B84	4	1119	
REA2	A	0000116C	4	580	
REA20	A	00001C1C	4	1150	
REA21	A	00001CB4	4	1181	
REA22	A	00001D4C	4	1212	
REA23	A	00001DE4	4	1243	
REA24	A	00001E7C	4	1274	
REA25	A	00001F14	4	1309	
REA26	A	00001FAC	4	1340	
REA27	A	00002044	4	1371	
REA28	A	000020DC	4	1402	
REA29	A	00002174	4	1433	
REA3	A	00001204	4	611	
REA30	A	0000220C	4	1464	
REA31	A	000022A4	4	1495	
REA32	A	0000233C	4	1526	
REA4	A	0000129C	4	642	
REA5	A	00001334	4	676	
REA6	A	000013CC	4	707	
REA7	A	00001464	4	738	
REA8	A	000014FC	4	769	
REA9	A	00001594	4	803	
READDR	A	0000001C	4	432	229
REG2LOW	U	000000DD	1	375	
REG2PATT	U	AABBCCDD	1	374	
RELEN	A	00000018	4	431	
RPTDWSAV	D	00000398	8	300	287 291
RPTERROR	I	0000032C	4	267	242
RPTSAVE	F	00000390	4	297	267 294
RPTSVR5	F	00000394	4	298	268 293
SKL0001	U	0000004E	1	187	203
SKT0001	C	0000022A	20	184	187 204
SVOLDPSW	U	00000140	0	123	
T1	A	000010B8	4	541	1554
T10	A	00001610	4	826	1563
T11	A	000016A8	4	857	1564
T12	A	00001740	4	888	1565
T13	A	000017D8	4	922	1566
T14	A	00001870	4	953	1567
T15	A	00001908	4	984	1568
T16	A	000019A0	4	1015	1569
T17	A	00001A38	4	1049	1570
T18	A	00001AD0	4	1080	1571
T19	A	00001B68	4	1111	1572
T2	A	00001150	4	572	1555
T20	A	00001C00	4	1142	1573
T21	A	00001C98	4	1173	1574
T22	A	00001D30	4	1204	1575
T23	A	00001DC8	4	1235	1576
T24	A	00001E60	4	1266	1577
T25	A	00001EF8	4	1301	1578
T26	A	00001F90	4	1332	1579
T27	A	00002028	4	1363	1580
T28	A	000020C0	4	1394	1581
T29	A	00002158	4	1425	1582

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
T3	A	000011E8	4	603	1556
T30	A	000021F0	4	1456	1583
T31	A	00002288	4	1487	1584
T32	A	00002320	4	1518	1585
T4	A	00001280	4	634	1557
T5	A	00001318	4	668	1558
T6	A	000013B0	4	699	1559
T7	A	00001448	4	730	1560
T8	A	000014E0	4	761	1561
T9	A	00001578	4	795	1562
TESTING	F	00001004	4	386	223
TNUM	H	00000004	2	424	222
TSUB	A	00000000	4	423	226
TTABLE	F	000023C0	4	1553	
V0	U	00000000	1	1618	
V1	U	00000001	1	1619	225
V10	U	0000000A	1	1628	
V11	U	0000000B	1	1629	
V12	U	0000000C	1	1630	
V13	U	0000000D	1	1631	
V14	U	0000000E	1	1632	
V15	U	0000000F	1	1633	
V16	U	00000010	1	1634	
V17	U	00000011	1	1635	
V18	U	00000012	1	1636	
V19	U	00000013	1	1637	
V1FUDGE	X	00001094	16	415	225
V101	X	000010E0	16	551	560
V1010	X	00001638	16	836	845
V1011	X	000016D0	16	867	876
V1012	X	00001768	16	898	907
V1013	X	00001800	16	932	941
V1014	X	00001898	16	963	972
V1015	X	00001930	16	994	1003
V1016	X	000019C8	16	1025	1034
V1017	X	00001A60	16	1059	1068
V1018	X	00001AF8	16	1090	1099
V1019	X	00001B90	16	1121	1130
V102	X	00001178	16	582	591
V1020	X	00001C28	16	1152	1161
V1021	X	00001CC0	16	1183	1192
V1022	X	00001D58	16	1214	1223
V1023	X	00001DF0	16	1245	1254
V1024	X	00001E88	16	1276	1285
V1025	X	00001F20	16	1311	1320
V1026	X	00001FB8	16	1342	1351
V1027	X	00002050	16	1373	1382
V1028	X	000020E8	16	1404	1413
V1029	X	00002180	16	1435	1444
V103	X	00001210	16	613	622
V1030	X	00002218	16	1466	1475
V1031	X	000022B0	16	1497	1506
V1032	X	00002348	16	1528	1537
V104	X	000012A8	16	644	653
V105	X	00001340	16	678	687
V106	X	000013D8	16	709	718

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
X22	F	00001D70	4	1217	1204
X23	F	00001E08	4	1248	1235
X24	F	00001EA0	4	1279	1266
X25	F	00001F38	4	1314	1301
X26	F	00001FD0	4	1345	1332
X27	F	00002068	4	1376	1363
X28	F	00002100	4	1407	1394
X29	F	00002198	4	1438	1425
X3	F	00001228	4	616	603
X30	F	00002230	4	1469	1456
X31	F	000022C8	4	1500	1487
X32	F	00002360	4	1531	1518
X4	F	000012C0	4	647	634
X5	F	00001358	4	681	668
X6	F	000013F0	4	712	699
X7	F	00001488	4	743	730
X8	F	00001520	4	774	761
X9	F	000015B8	4	808	795
XC0001	U	000002D0	1	207	199
ZVE7TST	J	00000000	9296	120	123 125 129 133 384 121
=A(E7TESTS)	A	00000498	4	362	213
=AL2(L' MSGMSG)	R	000004A2	2	365	312
=F' 1'	F	0000049C	4	363	248
=F' 64'	F	00000494	4	361	198
=H' 0'	H	000004A0	2	364	307

MACRO	DEFN	REFERENCES
FCHECK	73	180
PTTABLE	498	1552
VRR_C	453 1077	538 1108 600 1139 631 1170 665 1201 696 1232 727 1263 758 1298 792 1329 823 1360 854 1391 885 1422 919 1453 950 1484 981 1515 1012 1046

DESC	SYMBOL	SIZE	POS	ADDR
Entry: 0				
Image	IMAGE	9296	0000-244F	0000-244F
Region		9296	0000-244F	0000-244F
CSECT	ZVE7TST	9296	0000-244F	0000-244F

STMT	FILE NAME
1	/home/tn529/sharedvfp/tests/zvector-e7-01-MinMaxAvg.asm

** NO ERRORS FOUND **